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# *Burn-In Test Solutions*

# Laser Diode Burn In Test

## Why EADS North America Defense Test & Services for Burn-In Test?

EADS North America Defense Test & Services is the Supplier of Choice for standard and specialized electronic test equipment, providing instrumentation, software and turnkey test systems for a wide variety of commercial and military applications. Industry experience includes laser diode and micro-processor burn-in test, automotive, digital, and engine test.

## Semiconductor Burn In Test

The 5030 Burn-In Test System is a large-scale configurable burn-in system for high-volume production of semiconductor devices. The Model 5030 can simultaneously burn in up to 32 different work orders, each with its own burn-in recipe consisting of voltage, temperature, burn-in time, digital test, etc. Multiple input and output lanes allow cascading of work orders to maximize tool utilization.



Sophisticated DUT-level controls allow for automatic folding of DUT voltage if current limits or temperature limits are exceeded. Parametrics from all 768 devices can be logged to a file every 400 milliseconds. Highly efficient two-phase refrigeration-based cooling allows the 5030 to achieve unprecedented DUT power levels while lowering electricity bills.



Laser diode test systems feature an intuitive Graphical User Interface, with source code provided for long-term maintainability. Device fixturing is designed to integrate with multiple workstations in manufacturing process flows. With custom interfaces to manufacturing and corporate databases, the systems are ideal for burn-in, Bellcore reliability and characterization uses.

## GaAs FET Burn In Test

EADS North America Defense Test & Services developed a FET burn-in system based on the Racal Instruments 1256 Switching System (shown at left) and Racal Instruments 1260-114 Digital I/O Plug-In Modules. The system provides up to 32 positive and 32 negative bias voltages to power FETs for extended burn-in.

